

#7/B  
KENYON  
8/30/03

PATENT  
Docket No.: 1743/193

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT : Tohru Ishitani

SERIAL NO. : 09/943,262

FILED : August 30, 2001

FAX RECEIVED

FOR : Scanning Charged-Particle Microscope

JUL 30 2003

ART UNIT : 2853

TECHNOLOGY CENTER 2800

EXAMINER : Lam S. Nguyen

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

SUPPLEMENTAL AMENDMENT

SIR:

Supplemental to the response filed on May 19, 2003, kindly amend the above-identified application as follows: